

Notice of References Cited

Application/Control No.

10/674,496

Applicant(s)/Patent Under
Reexamination
ONISHI, AKIKO

Examiner

Peter K. Huntsinger

Art Unit

2625

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,351,320	02-2002	Shin, Helen Haekyung	358/1.9
	B	US-			
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	D	US-			
	E	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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